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(54) Support method, quality control method, and device therefor

(57) The present invention quickly resolves troubles in an analysis device to perform effective external quality control. An analysis device (2) and a control device (1) are connected by a network (3). Error data and sample data taken from a measurement of a quality control substance are transmitted from the control device (1) to the analysis device (2). The analysis device (2) is made to be remotely operable from the control device (1) and when troubles arise repair from the control device (1) is possible. The control device (1) analyzes sample data, and provides the analysis results to a web page. The analysis device (2) accesses the web page using a WWW browser, and can perform external quality control in real time.

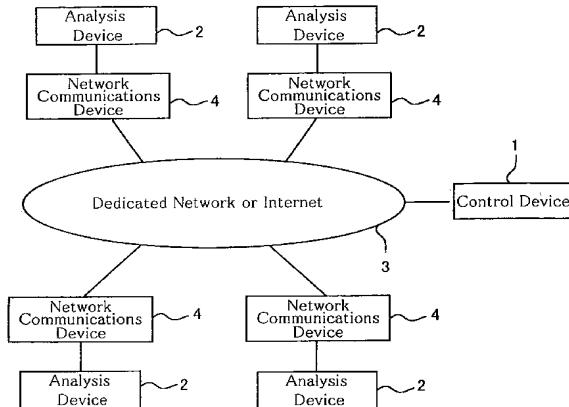


Fig. 1



EUROPEAN SEARCH REPORT

Application Number
EP 08 00 5920

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The present search report has been drawn up for all claims			
2	Place of search The Hague	Date of completion of the search 21 November 2008	Examiner Swarén, Peter
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Application Number

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ON EUROPEAN PATENT APPLICATION NO.**

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